Supplementary Information

Supplementary Experiment 1

*PXRD test of amorphous form of loratadine crystallized in isopropyl ether*

Approximately 0.2 g amorphous form of loratadine was crystallized from isopropyl ether (40 mL). Powder X-ray diffraction data were collected using an X-ray diffractometer (XRD-6100, Shimadzu Co., Japan) with a Cu Kα radiation source being operated at 40 kV and 30 mA. The powder samples were packed into the sample holder and scanned from 5 to 45° 2θ at a step size of 0.02° with a dwell time of 0.06 s, respectively. Data analysis was performed using JADE software (version 5, Materials Data Inc., Livermore, Canada). And the PXRD patterns are shown in *Supplementary Fig. 1*.  

\[<\text{Supplementary Fig. 1. PXRD patterns of sample 1 and A form of loratadine. After amorphous form of loratadine crystallized in isopropyl ether, we gained crystal which have same PXRD with form A.}>\]

Supplementary Experiment 2
Polycrystalline transform was performed by differential scanning calorimeter (DSC Q20, TA Instruments, Inc., USA). Temperature and enthalpy of DSC were calibrated using indium phase transition (99.99% pure; heat of fusion, 28.45 J/g; melting point, 156.61 °C). Approximate sample was weighted into a standard aluminum pan and sealed with aluminum lid (pan: 900786-901; lid: 900779-901), and another empty aluminum pan was sealed as reference. The reference pan and the sample pan were placed into the DSC furnace. Under a stream of N$_2$ gas (25 mL/min), the samples were obtained as follow:

*Sample 2:* The amorphous sample was heated from 25 °C to 125 °C at 0.5 °C/min, then cooled to ambient temperature at 2 °C/min.

*Sample 3:* The form B sample was ramped to 120 °C at 0.5 °C/min, then cooling to room temperature at 2 °C/min.

Powder X-ray diffraction (PXRD) data were collected using an X-ray diffractometer (XRD-6100, Shimadzu Co., Japan) with a Cu Kα radiation source being operated at 40 kV and 30 mA. After ground into powder, the samples were packed into the sample holder and scanned from 5 to 45° 2θ at a step size of 0.02° with a dwell time of 0.06 s. Data analysis was performed using JADE software (version 5, Materials Data Inc., Livermore, Canada). And the diffraction patterns are shown in *Supplementary Fig. 2.*
Supplementary Fig. 2. The PXRD patterns. Sample 2: The amorphous sample was heated from 25 °C to 125 °C at 0.5 °C/min, then cooled to ambient temperature at 2 °C/min. Sample 3: The form B sample was ramped to 120 °C at 0.5 °C/min, then cooling to room temperature at 2 °C/min.